

16 channel Analogue Test Station Module

V-I test capability

Number of test channels:	16 + 2 probes and references
Test voltage:	2 V to 50 V peak to peak
Voltage resolution:	8 to 12 bits
Test frequency:	37.5 Hz to 12 kHz
Test current:	1 μ A to 150 mA
Source impedance:	100 Ohm to 1 M
Test waveforms:	Sine, square, triangle, ramp, pulse
Waveform modes:	V-I, V-T, I-T
Waveform display:	Multi-plot with single waveform zoom
Waveform comparison:	Automatic comparison algorithm for good and bad boards using live probes or saved data
V-I comparison tolerance:	50 mV to 500 mV with 50 mV resolution
Package support:	DIL, SOIC, PLCC, QFP and variants with MultiProbes
Pulse output:	Positive, negative or bipolar for thyristors/triacs
Pulse amplitude:	Adjustable to +/-10 V
Calibration:	Automatic

Accessories

Standard	1 x 16 way test clip 1 x 24 way test cable 2 x Ground leads 2 x Pulse leads 1 x Blue V-I probe and adapter 1 x Yellow V-I probe and adapter 1 x SMD test tweezer set
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Options

Internal fitting	PCI interface
External fitting	MultiLink case (cost option) with serial or parallel connection External case (cost option) which can hold up to 4 SYSTEM 8 modules.

The ABI development team strive continually to improve their products for the benefit of the customer. The specification of current products may therefore vary from that described in this brochure.



Making Light Work

ABI Electronics Limited
Dodworth Business Park
Dodworth, Barnsley
South Yorkshire S75 3SP
United Kingdom
Tel: +44 1226 207420
Fax: +44 1226 207620
www.abielelectronics.co.uk